Applicant(s)/Patent Under Application/Control No. Reexamination 10/800,827 CHEN ET AL. **Notice of References Cited** Examiner Art Unit Page 1 of 1 2627 Kezhen Shen **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0088440 A1	05-2004	Chen et al.	710/001
*	В	US-2005/0050100 A1	03-2005	Chin, Yuan-Chang	707/104.1
*	C	US-2004/0252967 A1	12-2004	Sheu et al.	386/046
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Ξ	US-			
	1	US-			
	J	US-			
	K	US-			
	٦	US-		•	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	Ŕ				,	
	S					
	Т					

NON-PATENT DOCUMENTS

		· · · · · · · · · · · · · · · · · · ·				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ					
	v					
	w					
	×					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.